

02/14/01

ISSUE CLASSIFICATION	
Class	Subclass

PATENT NUMBER

O.I.P.E.	PATENT DATE
SCANNED <i>tc1</i> Q.A. <i>gyl</i>	

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/681186	D	378	58	2876-2882	Kao

APPLICANTS

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TIME

Method for examining structures on a semiconductor substrate

PTO-2040
12/99

ISSUING CLASSIFICATION											
ORIGINAL				CROSS REFERENCE(S)							
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
INTERNATIONAL CLASSIFICATION											

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____				ISSUE FEE	
	_____ (Primary Examiner) _____ (Date)	Amount Due	Date Paid		
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner) _____ (Date)			ISSUE BATCH NUMBER	
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